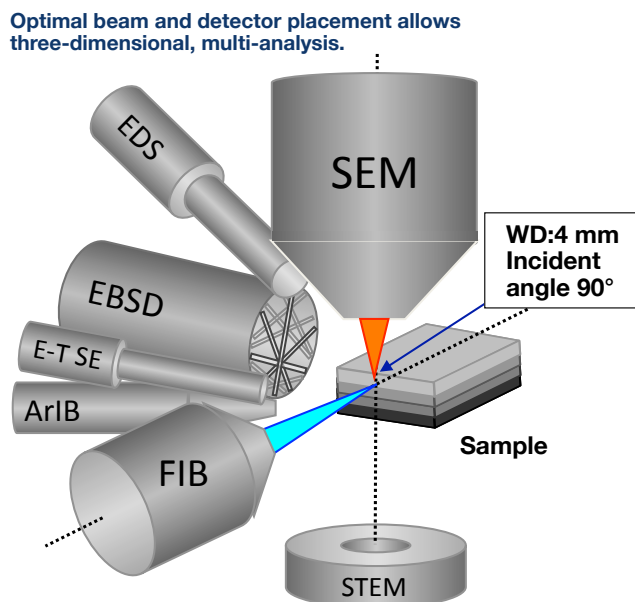


NX9000 L-Shape FIB-SEM Three-Dimensional Analytical System

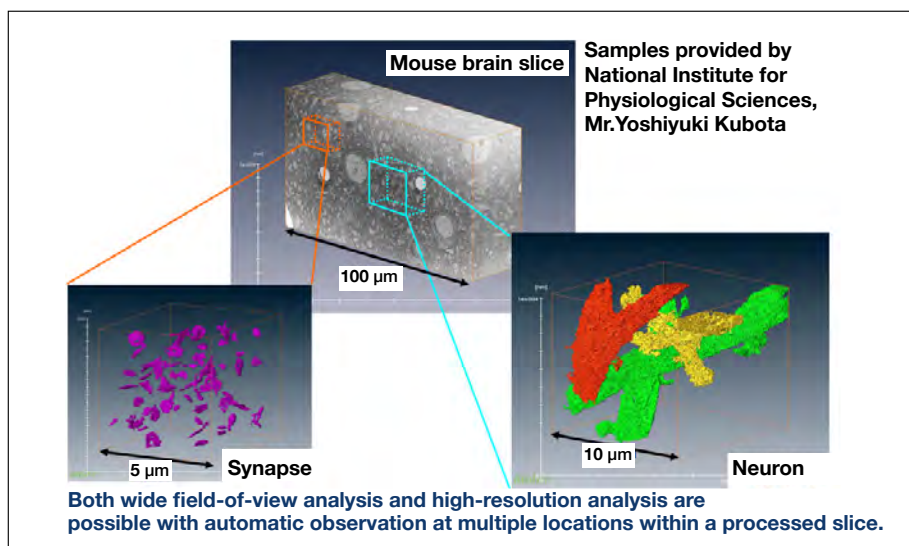
The NX9000 is a processing and observation system for three-dimensional analysis, with an FIB and SEM arranged perpendicular to each other. Optimal positioning of the FIB-SEM columns and detection systems allows high-resolution, three-dimensional, multi-analysis.

Main features

- (1) New FIB and new SEM column allow high-speed, highly precise processing and high-resolution observation.
- (2) A Multi-Cut & See function allows continuous, automatic acquisition of observed images at multiple locations within a processed slice, which accomplish with both wide field-of-view analysis and high-resolution analysis.
- (3) Multi-axis/environmental holders for Hitachi TEM can be installed to allow linkage between equipments or use of various specimens.



Unit schematic of L-Shape FIB-SEM NX9000



Example of three-dimensional observation of biological specimen with "Multi-Cut & See" function